Notice of References Cited Application/Control No. 10/808,552 Examiner Anabel M. Ton Applicant(s)/Patent Under Reexamination YATSUDA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0093820	07-2002	Pederson, John C.	362/241
*	В	US-2005/0213341	09-2005	Wehner, Kathryn M.	362/545
*	С	US-2004/0202006	10-2004.	Pien, Shou-Wei	362/545
*	D	US-2004/0196663	10-2004	Ishida et al.	362/539
*	E	US-6,960,007	11-2005	Ishida et al.	362/538
	F	US-			
	G	US-			
	Н	US-			
	i	US-			
	J	US-			
	Κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т	* (**				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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